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ABSTRACT OF THE DISCLOSURE

B A scanned-stylus atomic force microscope (AFM) employing
the optical lever technique, and method of operating the same.
The AFM of the invention includes a light source and a scanned
optical assembly which guides ^a light ~~beam~~ emitted from the
B ~~laser~~ ^{light} source onto a point on ~~said~~ ^a cantilever during scanning
B thereof. A moving ~~laser~~ ^{light} beam is thus created which will
automatically track the movement of the cantilever during
scanning. The invention also allows the ~~laser~~ ^{light} beam to be used
B to measure, calibrate or correct the motion of the scanning
mechanism, and further allows viewing of the sample and
cantilever using an optical microscope.

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